


<b>Search Notes</b>  	<b>Application/Control No.</b>  10541569	<b>Applicant(s)/Patent Under Reexamination</b>  KIM ET AL.
	<b>Examiner</b>  EVA Y PUENTE	<b>Art Unit</b>  2611

SEARCHED			
Class	Subclass	Date	Examiner
375	270,240,252,265,286	8/28/09	E.P
714	756,755,792	8/28/09	E.P

SEARCH NOTES		
Search Notes	Date	Examiner
updated search; IEEE	8/28/09	E.P

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
714	756,755,792	8/28/09	E.P

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